

<b>Notice of References Cited</b>	Application/Control No. 10/784,144	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Khiem D. Nguyen	Art Unit 2823	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,300,676	10-2001	Kawai, Hiroshi	257/678
*	B	US-2004/0035917	02-2004	Koopmans, Michel	228/215
*	C	US-2003/0102566	06-2003	Farnworth, Warren M.	257/774
*	D	US-2002/0088986	07-2002	Kayama et al.	257/99
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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